

ABSTRACT OF DISCLOSURE

A control module for an electronic test probe is built including a switch or other control device coupled to the test equipment, and electrically isolated from the probe tip, such that a user may make a measurement with the probe, and then without moving the probe, activate the control device to change the configuration of the test equipment. This allows a user to make different measurements of the same part of a device without having to remove the probe from the device to change the configuration of the test equipment.

Also, since the control device is electrically isolated from the probe tip, activating the control device does not electrically interfere with the voltage at the probe tip. Further, the control device body is configured to non-permanently mechanically couple with the test probe, so that the same control device may be used with a plurality of different test probes.